

### University of California College of Engineering Department of Electrical Engineering and Computer Sciences

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WeFr 2-3:30pm

Fr, February 19, 6:30-8:00pm

# EECS 141: SPRING 10—MIDTERM 1

NAME	Last	First
SID		
		<b>Problem 1 (15):</b>
		<b>Problem 2 (12):</b>
		<b>Problem 3 (15):</b>
		<u> </u>
		Total (42)

# [PROBLEM 1] CMOS NON-INVERTING BUFFER (15 pts)

The following circuit can be seemed as a "DIGITAL NON-INVERTING BUFFER".

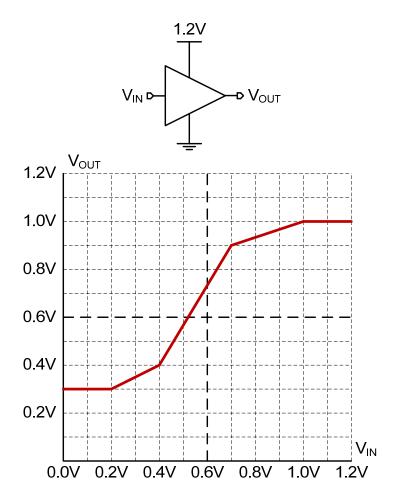


Fig.1 (a) DIGITAL BUFFER & VTC

(a) (3pts) Compute  $V_{\text{IL}},\,V_{\text{IH}},\,V_{\text{OL}},\,V_{\text{OH}},\,NM_{\text{L}},\,\text{and}\,\,NM_{\text{H}}.$ 

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(i) V<sub>IL</sub> = (ii) V<sub>IH</sub> = (iii) V<sub>OL</sub> = (iv) V<sub>OH</sub> = (v) NM<sub>L</sub> = (vi) NM<sub>H</sub> =
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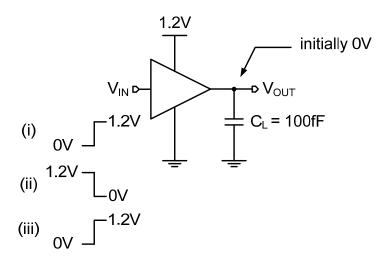


Fig.1 (b) One-stage DIGITAL BUFFER with 100fF C<sub>L</sub>

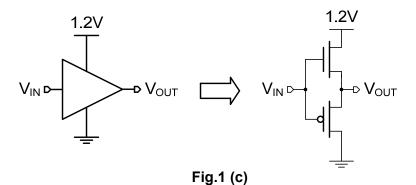
(b) (6pts) For Fig.1.(b), the output voltage,  $V_{OUT}$ , is initially discharged,  $V_{OUT}$ =0. You may ignore the intrinsic capacitance, or diffusion capacitance, of the buffer.

Find the energy dissipated in the buffer during the first 0 to 1.2V step input (i), First E<sub>DISS</sub>.

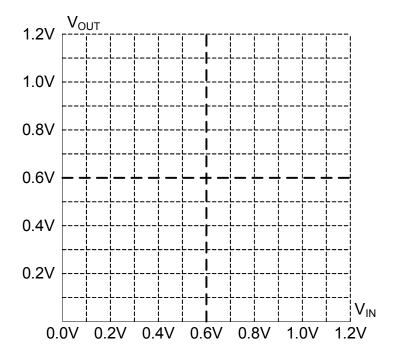
Then, after the output reaches its final value, a 1.2V to 0 step is applied to the input (ii). Find the <u>energy dissipated in the buffer</u>, **Second E**<sub>DISS</sub>.

A second 0 to 1.2V step follows (iii). Find again the energy dissipated in the buffer (Third E<sub>DISS</sub>).

(ii) 2nd 
$$E_{DISS} =$$



(c) (4 pts) One engineer tried to develop a transistor-level implementation of the buffer as shown in Fig.1(c). Draw the VTC of the circuit where VIN goes from 0V to 1.2V and then goes back to 0V. Here, the  $V_{TN}=|V_{TP}|=0.2V$ ,  $R_{OFF}=\inf$ , and no body effect, that is the threshold voltage is not dependent upon the voltage of the body.



(d) (2pts) Can the gate couple of words wh	e of Fig 1.c still be con ny or why not.	nsidered a digital	gate (or, is it still	regenerative)?	Explain in	а

#### [PROBLEM 2] RING OSCILLATOR (12pts)

Consider the 5-stage ring oscillator shown in Fig.2a, which is used to generate a clock signal. The input gate capacitance of a minimum-sized inverter (size=1) is  $C_{IN}$ =10fF, while  $R_{ON,N}$ = $R_{ON,P}$ =7.22k $\Omega$ , and  $R_{OFF}$ =inf. Assume that the input capacitance is proportional to its size, and  $R_{ON}$  is inversely proportional to its size. The diffusion capacitance, or intrinsic capacitance, of inverter is the same as the gate capacitance,  $\gamma$ =1. Ignore resistance and capacitance of the wires between the inverters.

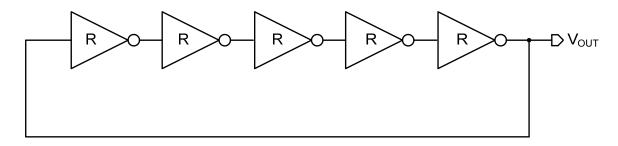
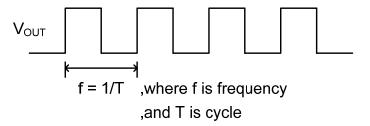


Fig.2 (a) 5-stage Ring Oscillator

(a) (6pts) Determine the oscillation frequency of this circuit at  $V_{OUT}$  for R=1 (that is, using unit inverters). Determine also the power dissipation of the circuit  $P_{SUPPLY}$  for VDD = 1.2V. You should take into account the gate and diffusion capacitances.



f = P<sub>SUPPLY</sub> = (b) (6pt) Determine the oscillation frequency of ring oscillator and as well as the power dissipation, when the inverters are sized at R=2, R=4, and R=8, respectively. Please normalize your results with respect to  $f_{R=1}$  and  $P_{SUPPLY,R=1}$ .

R	<b>f</b> <sub>R</sub> / <b>f</b> <sub>R=1</sub>	P <sub>SUPPLY,R</sub> / P <sub>SUPPLY,R=1</sub>
2		
4		
8		

## [PROBLEM 3] COMPLEX LOGIC AND LOGICAL EFFORT (15 pts)

(a) (2pts) Implement the logic function  $F = \overline{A \cdot B + C}$  by using a complex static CMOS Gate. Place the PMOS and NMOS driven by input A closest to the output node, F, in your transistor stacks.

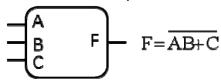
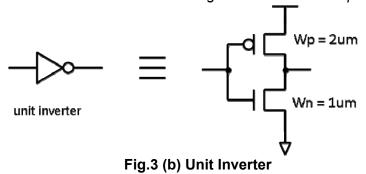


Fig.3 (a) Complex Gate

(b) (3pts) The unit inverter is shown in Fig. 3(b). Assume that  $C_D=C_G=2fF/\mu m$ . Size the transistors of the complex gate in (a) such that the worst cast driving strength for all inputs is the same as a unit inverter. Give the width of all transistors in units of um. Determine the logical effort for each input?



Sizes of all transistors: (In units of um)

LE<sub>A</sub>=

LE<sub>B</sub>=

LE<sub>c</sub>=

(c) (5 pts) In Fig. 3(c), we insert two unit-sized inverters to drive input A of the complex gate. For the complex gate, use the sizes of transistors that you derived in (b). Assume that  $C_D = C_G = 2fF/\mu m$ . The delay, Td1, measured from *In* to **X** is 40ps. What is the delay, Td2, measured from *In* to **Y**?

(Note: If you don't know the answer for (a) and (b), replace the complex gate with a 3-input NOR gate,  $F = \overline{A + B + C}$ . Size the transistors of 3-input NOR gate such that the worst cast driving strength for all inputs is the same as a unit inverter.)

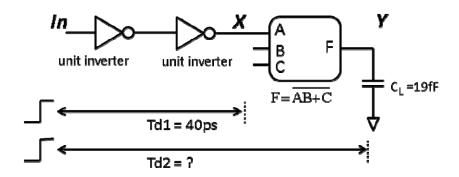


Fig.3 (c) Delay of the Complex Gate

Td2=

(d) (5pts) The complex gate that you designed in (a) is used in the critical path of the logical network shown in Fig. 3(d). Assume that  $C_D=C_G=2fF/\mu m$ . What is the total path effort from In to Out? In order to minimize the delay, what should the effective fan-out per stage for this chain of gates be?

(Note: If you don't know the answer in (a) and (b), replace the complex gate with a 3-input NOR gate,  $F = \overline{A + B + C}$ .)

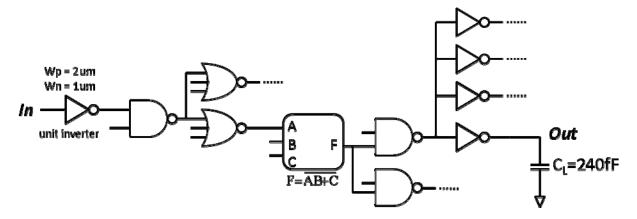


Fig.3 (d) Critical Path of Combinational Logic

PE = EF =